

AP60N03GP-VB Datasheet N-Channel 30 V (D-S) MOSFET

PRODUCT SUMMARY					
V _{DS} (V)	30				
$R_{DS(on)}$ (Ω) at V_{GS} = 10 V	0. 007				
$R_{DS(on)}$ (Ω) at V_{GS} = 4.5 V	0. 010				
I _D (A)	70				
Configuration	Single				
Package	TO-220AB				

TO-220AB

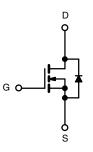
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G D S Top View

FEATURES

- TrenchFET[®] power MOSFET
- Package with low thermal resistance
- + 100 % $\rm R_g$ and UIS tested





N-Channel MOSFET

PARAMETER		SYMBOL	LIMIT	UNIT
Drain-Source Voltage		V _{DS}	30	
Gate-Source Voltage	V _{GS}	± 20	V	
Continuous Drain Current	T _C = 25 °C ª	1	70	A
	T _C = 125 °C	ID	50	
Continuous Source Current (Diode Conduct	ion) ^a	I _S	70	
Pulsed Drain Current ^b	I _{DM}	250		
Single Pulse Avalanche Current	L = 0.1 mH	I _{AS}	33	
Single Pulse Avalanche Energy		E _{AS}	54	mJ
Maximum Power Dissipation ^b	T _C = 25 °C	P	71	w
	T _C = 125 °C	P _D	23	vv
Operating Junction and Storage Temperatu	re Range	TJ, T _{stg}	-55 to +175	°C

THERMAL RESISTANCE RATINGS				
PARAMETER		SYMBOL	LIMIT	UNIT
Junction-to-Ambient	PCB Mount ^c	R _{thJA}	50	°C/W
Junction-to-Case (Drain)		R _{thJC}	2.1	0/10

Notes

- a. Package limited.
- b. Pulse test; pulse width $\leq 300~\mu s,~duty~cycle \leq 2~\%.$
- c. When mounted on 1" square PCB (FR4 material).

SPECIFICATIONS ($T_C = 25 \ ^{\circ}C$,	unless otherw	vise noted)					
PARAMETER	SYMBOL	TES	T CONDITIONS	MIN.	TYP.	MAX.	UNIT
Static						•	
Drain-Source Breakdown Voltage	V _{DS}	V_{GS} = 0 V, I_D = 250 μ A		30	-	-	v
Gate-Source Threshold Voltage	V _{GS(th)}	V _{DS} =	= V _{GS} , I _D = 250 μA	1.0		2.5	v
Gate-Source Leakage	I _{GSS}	V _{DS} =	0 V, V_{GS} = ± 20 V	-	-	± 100	nA
		$V_{GS} = 0 V$	V _{DS} = 30 V	-	-	1	
Zero Gate Voltage Drain Current	I _{DSS}	$V_{GS} = 0 V$	$V_{DS} = 30 \text{ V}, \text{ T}_{J} = 125 ^{\circ}\text{C}$	-	-	50	μA
		$V_{GS} = 0 V$	$V_{DS} = 30 \text{ V}, \text{ T}_{J} = 175 ^{\circ}\text{C}$	-	-	150	50 - A - - - - - - - - - - - - - - - - - -
On-State Drain Current ^a	I _{D(on)}	V _{GS} = 10 V	$V_{DS} \ge 5 V$	70	-	-	А
		V _{GS} = 10 V	I _D = 20 A	-	0.007	-	Ω
Durain Source On State Desistance a	P	V _{GS} = 10 V	I _D = 20 A, T _J = 125 °C	-	0.010	-	
Drain-Source On-State Resistance ^a	R _{DS(on)}	V _{GS} = 10 V	I _D = 20 A, T _J = 175 °C	-	0.014	-	
		$V_{GS} = 4.5 V$	I _D = 15 A	-	0.010	-	
Forward Transconductance b	g fs	V _{DS}	= 15 V, I _D = 15 A	-	100	-	S
Dynamic ^b		·					
Input Capacitance	C _{iss}			-	-	1500	
Output Capacitance	C _{oss}	$V_{GS} = 0 V$	$V_{DS} = 25 \text{ V}, \text{ f} = 1 \text{ MHz}$	-	-	260	pF
Reverse Transfer Capacitance	C _{rss}]		-	-	95	
Total Gate Charge ^c	Qg			-	46	75	
Gate-Source Charge ^c	Q _{gs}	V _{GS} = 10 V	$V_{DS} = 20 \text{ V}, I_D = 50 \text{ A}$	-	10	-	nC
Gate-Drain Charge ^c	Q _{gd}	1		-	8	-	
Gate Resistance	Rg	f = 1 MHz		1.3	2.8	4.5	Ω
Turn-On Delay Time ^c	t _{d(on)}			-	9	15	
Rise Time ^c	t _r	- V _{DD} =	= 20 V, R _I = 0.4 Ω	-	19	30	
Turn-Off Delay Time ^c	t _{d(off)}	$\frac{V_{DD} = 20 \text{ V}, \text{ R}_{L} = 0.4 \Omega}{I_{D} \cong 50 \text{ A}, \text{ V}_{\text{GEN}} = 10 \text{ V}, \text{ R}_{g} = 1 \Omega} - 26$		26	40	ns	
Fall Time ^c	t _f			-	10	15	1
Source-Drain Diode Ratings and Char	acteristics ^b						
Pulsed Current ^a	I _{SM}			-	-	200	Α
Forward Voltage	V _{SD}	I _F =	30 A, V _{GS} = 0 V	-	0.87	1.5	V

Notes

a. Pulse test; pulse width $\leq 300~\mu\text{s},$ duty cycle $\leq 2~\%.$

b. Guaranteed by design, not subject to production testing.

c. Independent of operating temperature.

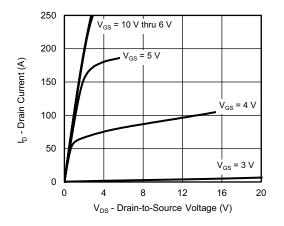
Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

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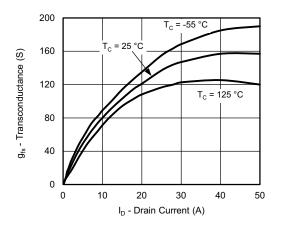
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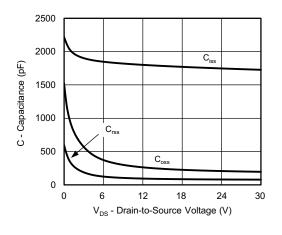
TYPICAL CHARACTERISTICS ($T_A = 25 \text{ °C}$, unless otherwise noted)



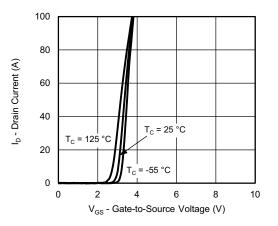
Output Characteristics



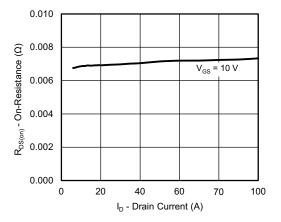
Transconductance



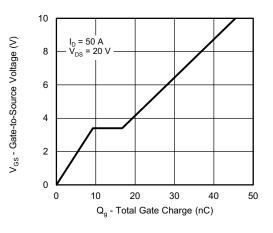
Capacitance



Transfer Characteristics



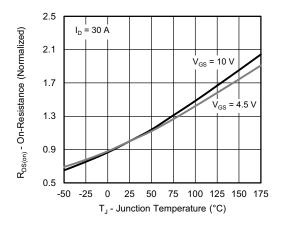
On-Resistance vs. Drain Current



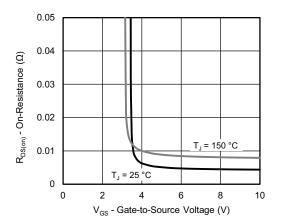
Gate Charge



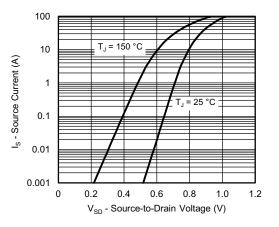
TYPICAL CHARACTERISTICS ($T_A = 25 \text{ °C}$, unless otherwise noted)



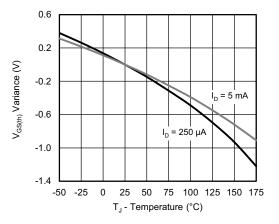
On-Resistance vs. Junction Temperature

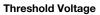


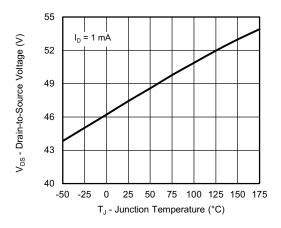
On-Resistance vs. Gate-to-Source Voltage



Source Drain Diode Forward Voltage



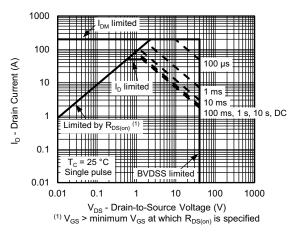




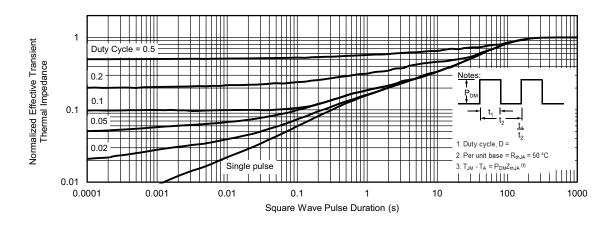
Drain Source Breakdown vs. Junction Temperature



THERMAL RATINGS ($T_A = 25 \text{ °C}$, unless otherwise noted)



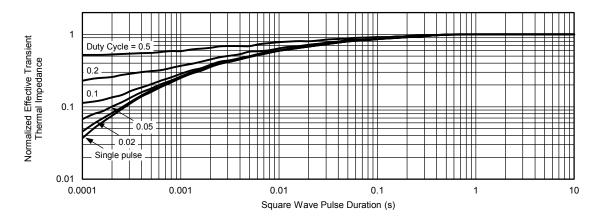
Safe Operating Area



Normalized Thermal Transient Impedance, Junction-to-Ambient



THERMAL RATINGS ($T_A = 25 \text{ °C}$, unless otherwise noted)



Normalized Thermal Transient Impedance, Junction-to-Case

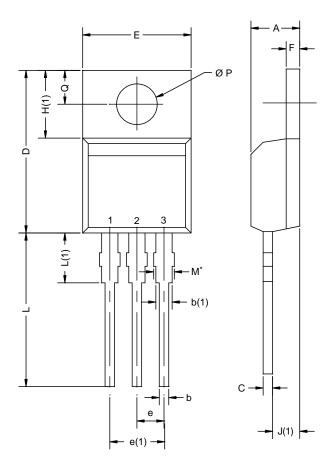
Note

- The characteristics shown in the two graphs
- Normalized Transient Thermal Impedance Junction to Ambient (25 °C)
- Normalized Transient Thermal Impedance Junction to Case (25 °C)

are given for general guidelines only to enable the user to get a "ball park" indication of part capabilities. The data are extracted from single pulse transient thermal impedance characteristics which are developed from empirical measurements. The latter is valid for the part mounted on printed circuit board - FR4, size 1" x 1" x 0.062", double sided with 2 oz. copper, 100 % on both sides. The part capabilities can widely vary depending on actual application parameters and operating conditions.







	MILLIN	IETERS	INCHES		
DIM.	MIN.	MAX.	MIN.	MAX.	
А	4.25	4.65	0.167	0.183	
b	0.69	1.01	0.027	0.040	
b(1)	1.20	1.73	0.047	0.068	
С	0.36	0.61	0.014	0.024	
D	14.85	15.49	0.585	0.610	
Е	10.04	10.51	0.395	0.414	
е	2.41	2.67	0.095	0.105	
e(1)	4.88	5.28	0.192	0.208	
F	1.14	1.40	0.045	0.055	
H(1)	6.09	6.48	0.240	0.255	
J(1)	2.41	2.92	0.095	0.115	
L	13.35	14.02	0.526	0.552	
L(1)	3.32	3.82	0.131	0.150	
ØР	3.54	3.94	0.139	0.155	
Q	2.60	3.00	0.102	0.118	
ECN: X12- DWG: 547	0208-Rev. N, 1	08-Oct-12			

Notes

 * M = 1.32 mm to 1.62 mm (dimension including protrusion) Heatsink hole for HVM



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